

# EVAL\_IGK048B041S\_GaN user guide

## CoolGaN™ BDS evaluation board

### About this document

#### Scope and purpose

This user guide provides an overview of the EVAL\_IGK048B041S\_GaN Evaluation Board including its main features, key components, pin assignments, and mechanical dimensions.

EVAL\_IGK048B041S\_GaN is a small daughter board designed specifically to assemble and evaluate SG-UFWLB-22 pin BGA (WLCSP-2.1x2.1 mm) package GaN bidirectional switch (BDS) [1]. The berg stick connector on this evaluation board is in line with the board-to-board connector on the EVAL\_GD\_BDS\_GaN Evaluation Board, which eventually can be used as a gate driver for this BDS board.

*Note: This board is sensitive to ESD and must be used only under laboratory conditions.*

#### Intended audience

This document is primarily intended to guide engineers evaluating bidirectional GaN switch performance.

### About this product group

#### Target applications

- [Consumer Electronics: USB-C chargers](#) and load switches
- [eFuses](#)
- [Battery management systems \(BMS\)](#)

#### Product family

[CoolGaN™ BDS](#) are normally-off monolithic GaN bidirectional switches with dual-gate independent control, enabling a common-drain structure for blocking voltage and current in both directions. They replace multiple unidirectional switches, reducing component count while improving switching speed and overall performance. CoolGaN™ BDS switches enhance efficiency, power density, and reliability in applications.

#### Evaluation Board

This board can be used during design-in process for evaluation and measurement of characteristics, and proof of data sheet specifications of the GaN BDS.

*Note: PCB and auxiliary circuits are NOT optimized for final customer design.*

## Safety precautions

## Safety precautions

Note: Please note the following warnings regarding the hazards associated with development systems.

Table 1 Safety precautions

|                                                                                     |                                                                                                                                                                                                                                                                                                                                                                                                                                                   |
|-------------------------------------------------------------------------------------|---------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
|    | <b>Warning:</b> The evaluation or reference board contains DC bus capacitors, which take time to discharge after removal of the main supply. Before working on the drive system, wait 5 minutes for capacitors to discharge to safe voltage levels. Failure to do so may result in personal injury or death. Darkened display LEDs are not an indication that capacitors have discharged to safe voltage levels.                                  |
|    | <b>Warning:</b> Remove or disconnect power from the drive before you disconnect or reconnect wires or perform maintenance work. Wait five minutes after removing power to discharge the bus capacitors. Do not attempt to service the drive until the bus capacitors have discharged to zero. Failure to do so may result in personal injury or death.                                                                                            |
|   | <b>Caution:</b> The heat sink and device surfaces of the evaluation or reference board may become hot during testing. Hence, necessary precautions are required while handling the board. Failure to comply may cause injury.                                                                                                                                                                                                                     |
|  | <b>Caution:</b> Only personnel familiar with the drive, power electronics and associated machinery should plan, install, commission and subsequently service the system. Failure to comply may result in personal injury and/or equipment damage.                                                                                                                                                                                                 |
|  | <b>Caution:</b> The evaluation or reference board contains parts and assembly's sensitive to electrostatic discharge (ESD). Electrostatic control precautions are required when installing, testing, servicing or repairing the assembly. Component damage may result if ESD control procedures are not followed. If you are not familiar with electrostatic control procedures, refer to the applicable ESD protection handbooks and guidelines. |
|  | <b>Caution:</b> A drive that is incorrectly applied or installed can lead to component damage or reduction in product lifetime. Wiring or application errors such as under sizing the motor, supplying an incorrect or inadequate AC supply, or excessive ambient temperatures may result in system malfunction.                                                                                                                                  |
|  | <b>Caution:</b> The evaluation or reference board is shipped with packing materials that need to be removed prior to installation. Failure to remove all packing materials that are unnecessary for system installation may result in overheating or abnormal operating conditions.                                                                                                                                                               |

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## 1 The board at a glance

### 1 The board at a glance

The EVAL\_IGK048B041S\_GaN Evaluation Board consists of a GaN bidirectional switch (BDS) in the SG-UFWLB-22 pin BGA (WLCSP-2.1x2.1 mm) package. The board has 3 Input terminals namely, D1 (Drain 1), D2 (Drain 2), and G (Gate).

The input terminals (berg stick) are in line with the board-to-board connector terminals on EVAL\_GD\_BDS\_GaN Evaluation Board.

#### 1.1 Scope

This evaluation board intended to evaluate bidirectional GaN switch performance.

#### 1.2 Block diagram

Figure 1 shows a typical block diagram of the EVAL\_IGK048B041S\_GaN Board consisting of 3 terminals D1, D2, and G.

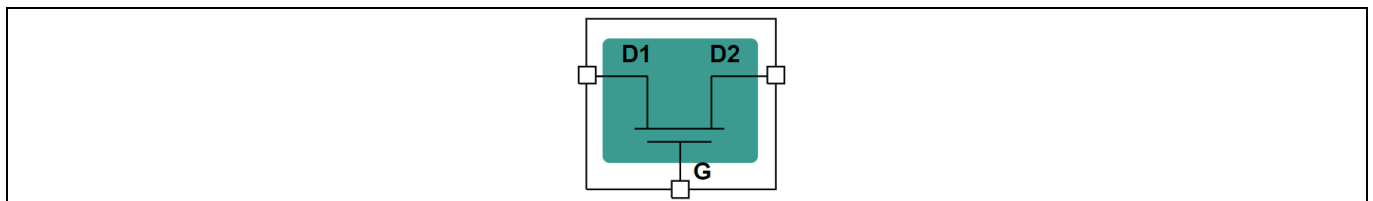


Figure 1 EVAL\_IGK048B041S\_GaN block diagram

#### 1.3 Main features

- 40 V, 4.2 mΩ GaN BDS switch (IGK048B041S) [1], specifically designed for SG-UFWLB 22 pin BGA (WLCSP-2.1 × 2.1 mm) package
- Maximum current of 20 A

#### 1.4 Board parameters and technical data

Table 2 EVAL board parameters

| Parameter                       | Symbol                 | Conditions              | Value |      |      | Unit |
|---------------------------------|------------------------|-------------------------|-------|------|------|------|
|                                 |                        |                         | Min   | Nom. | Max. |      |
| Drain-drain on state Resistance | $R_{DD(on)}$           | $V_{GD} = 5V, I_D = 5A$ | –     | 4.2  | 4.8  | mΩ   |
| Continuous drain-drain voltage  | $V_{D1D2}$             | –                       | –     | –    | 40   | V    |
| Gate-drain voltage              | $V_{GD1}$ or $V_{GD2}$ | –                       | -40   | –    | 6    | V    |
| Drain current                   | $I_{dd}$               | $T_{amb} = 25^{\circ}C$ | –     | –    | 20   | A    |

##### System environment

|                     |            |   |   |    |   |    |
|---------------------|------------|---|---|----|---|----|
| Ambient temperature | $T_{amb.}$ | – | – | 25 | – | °C |
|---------------------|------------|---|---|----|---|----|

##### PCB characteristics

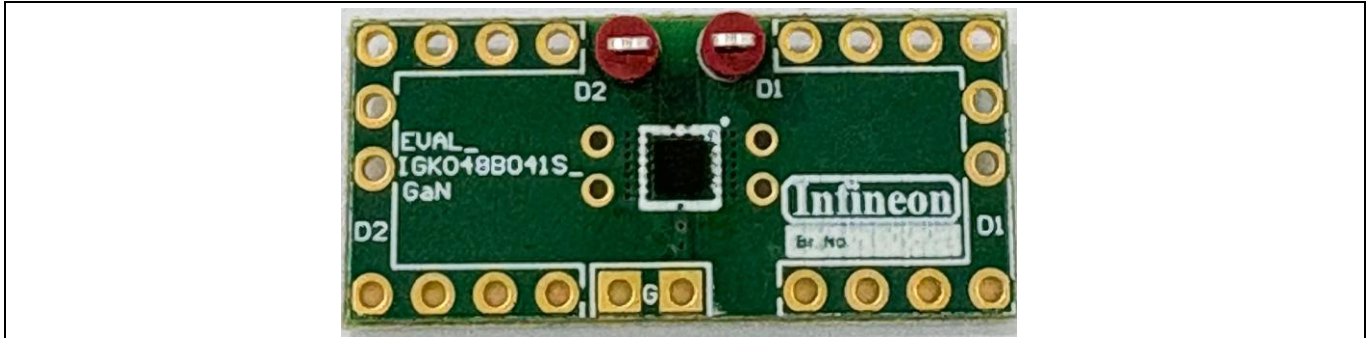
|            |   |        |   |      |   |    |
|------------|---|--------|---|------|---|----|
| Dimensions | L | Length | – | 27.7 | – | mm |
|            | W | Width  | – | 12.5 | – | mm |
|            | H | Height | – | 7.6  | – | mm |

## 1 The board at a glance

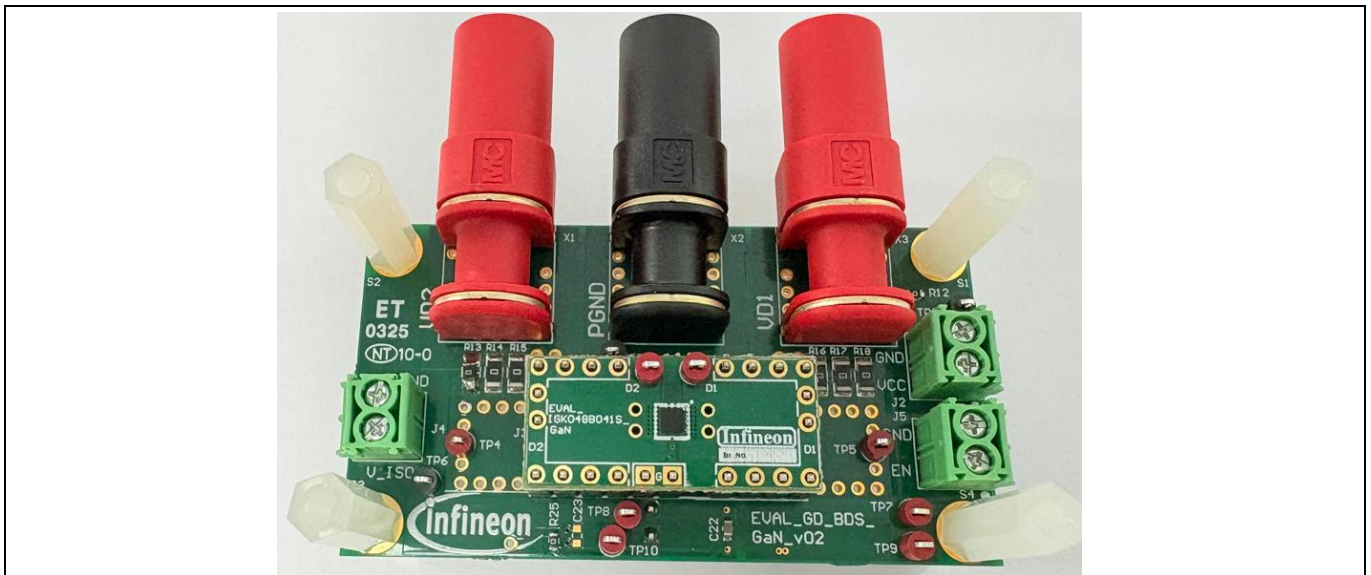
| Parameter        | Symbol | Conditions                    | Value |      |      | Unit |
|------------------|--------|-------------------------------|-------|------|------|------|
|                  |        |                               | Min   | Nom. | Max. |      |
| No. of layers    | –      | –                             | –     | 4    | –    | –    |
| PCB thickness    | –      | –                             | –     | 1.6  | –    | mm   |
| Copper thickness | –      | All layers                    | –     | 1    | –    | oz.  |
| Weight           | –      | Weight of entire PCB assembly | –     | –    | –    | g    |
| Material         | –      | FR-4, RoHS-compliant          |       |      |      |      |

## 2 System and functional description

This evaluation board is designed to evaluate a single GaN BDS in the SG-UFWLB-22 pin BGA (WLCSP-2.1x2.1 mm) package.



**Figure 2** EVAL\_IGK048B041S\_GaN Evaluation Board



**Figure 3** EVAL\_IGK048B041S\_GaN as a daughter board for EVAL\_GD\_BDS\_GaN gate driver evaluation board

The GaN BDS switch in this evaluation board can be used along with the gate driver evaluation board (such as EVAL\_GD\_BDS\_GaN) to drive this common-source configuration.

When the gate is referenced to D2 and  $V_{GD2}$  exceeds  $V_{GD(th)}$  of the GaN BDS switch, bidirectional current flow is enabled. With  $V_{GD2} = 5$  V, current can flow in both directions, with minimal voltage drop ( $R_{ON} \times I_{Load}$ ) and low power loss. If the gate signal is off with respect to D2 (i.e.,  $V_{GD2} = 0$  V), the channel acts like a diode, permitting conduction only from D2 to D1 with a higher voltage drop (2 to 2.5 V) [2].

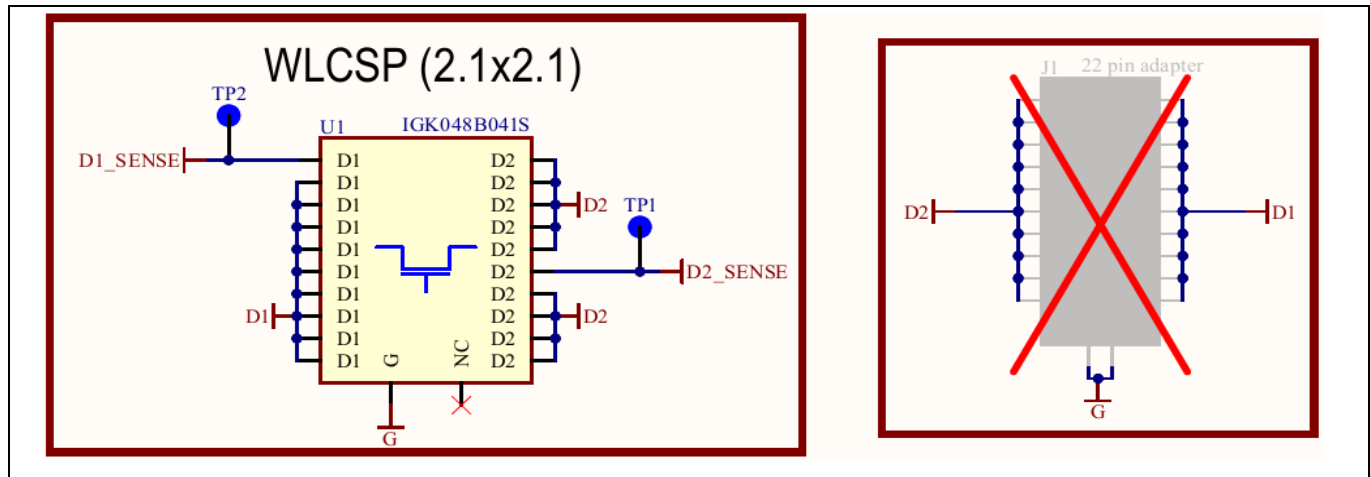
Similarly, when the gate is referenced to D1 and  $V_{GD1}$  exceeds  $V_{GD(th)}$ , again the bidirectional flow is enabled. When the gate is turned off with respect to D1 (i.e.  $V_{GD1} = 0$  V), the channel acts like a diode in other direction and the conduction will be possible from D1 to D2 with a higher voltage drop [2].

Thus, when the current direction is fixed, then referencing to a particular ground reference helps to control the GaN BDS switch effectively [2].

### 3 System design

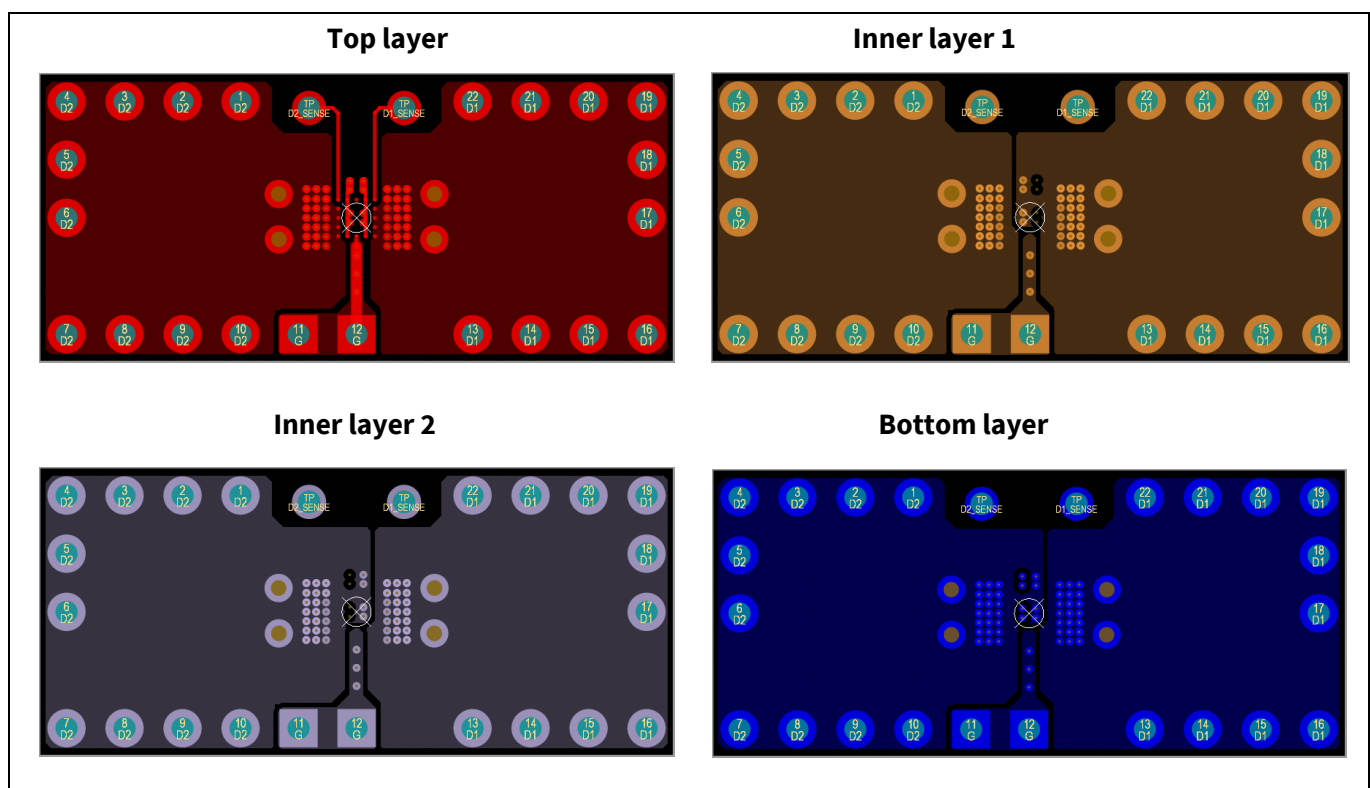
### 3 System design

### 3.1 Schematics



**Figure 4** EVAL\_IGK048B041S\_GaN schematics

### 3.2 Layout



**Figure 5** EVAL\_IGK048B0s41S\_GaN layout (top view)

### 3 System design

#### 3.3 Bill of materials

The complete bill of materials is available on the download section of the board homepage. A log-in is required to download this material.

**Table 3 BOM of the most important/critical parts of the evaluation or reference board (example)**

| S. No. | Ref designator | Description                       | Manufacturer          | Manufacturer P/N | Populated |
|--------|----------------|-----------------------------------|-----------------------|------------------|-----------|
| 1      | Q1             | 40 V 4.2 mΩ GaN BDS Common Source | Infineon Technologies | IGK048B041S      | Yes       |

#### 3.4 Connector details

**Table 4 Connectors**

| Pin | Label                    | Function                   |
|-----|--------------------------|----------------------------|
| D2  | J1 – pins 1, 2, 9, 10    | Drain-2 power input/output |
| D1  | J1 – pins 13, 14, 21, 22 | Drain-1 power input/output |
| G   | J1 – pins 11, 12         | Gate                       |

## 4 System performance

## 4 System performance

## 4.1 Test points

Table 5 Test points

| TP No. | Net        | Description                      |
|--------|------------|----------------------------------|
| TP1    | D2 – Sense | Test point for Drain-2 Ron Sense |
| TP2    | D1 – Sense | Test point for Drain-1 Ron Sense |

## 4.2 BDS – Independent evaluation

## 4.2.1 Test setup

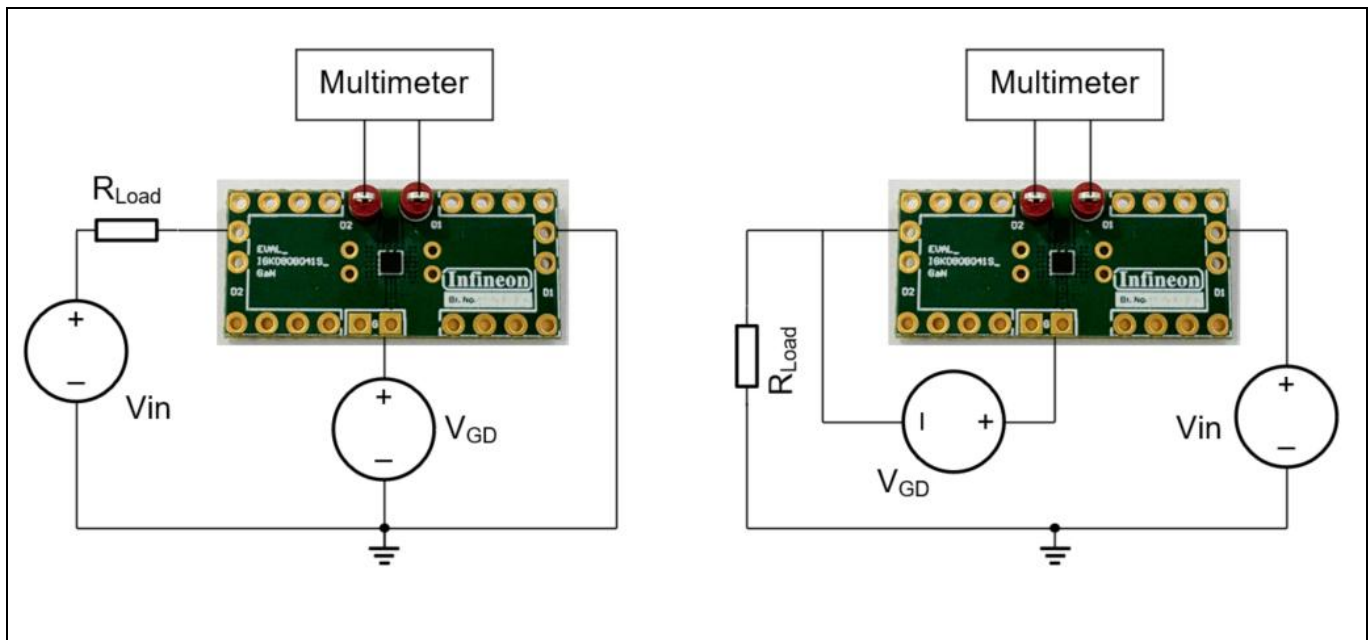


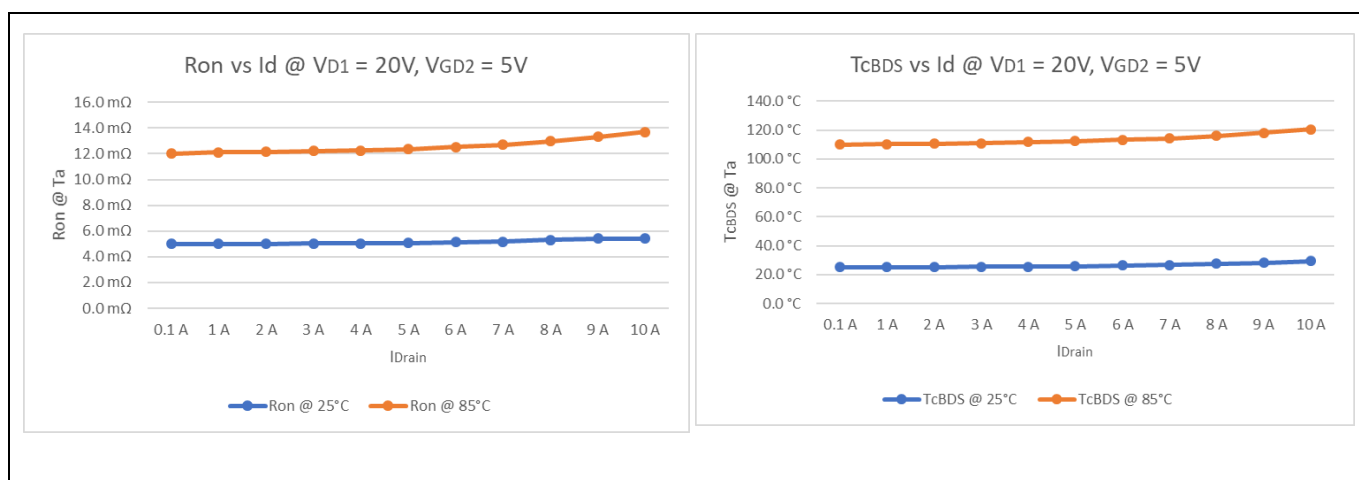
Figure 6 Test setup

Figure 6 represents the test setups to validate the GaN BDS in the EVAL\_IGK048B041S\_GaN Evaluation Board and test its operation at the required conditions. The input supply ( $V_{in}$ ) can be given to either of the Drain potentials i.e. D1 or D2 and the gate voltage is given with respect to the other drain as shown in Figure 6. Also, BDS can be used in either the low or high side configuration, provided that the gate voltage needs to be given with respect to drain potential that is not connected to the input supply.

## 4 System performance

4.2.2 On-state resistance ( $R_{on}$ ) vs. drain current ( $I_{drain}$ )Table 6 Measurement results -  $R_{on}$ ,  $T_c$  vs.  $I_d$  at  $V_{D1} = 20$  V and varying ambient temperature

| $V_{D1} = 20$ V, $V_{GD2} = 5$ V | $T_{amb}=25^{\circ}\text{C}$ |                         | $T_{amb}=85^{\circ}\text{C}$ |                         |
|----------------------------------|------------------------------|-------------------------|------------------------------|-------------------------|
| $I_{Drain}$                      | $R_{on}$                     | $T_{CBDS}$              | $R_{on}$                     | $T_{CBDS}$              |
| 0.1 A                            | 5.0 m $\Omega$               | 25.0 $^{\circ}\text{C}$ | 7.0 m $\Omega$               | 85.0 $^{\circ}\text{C}$ |
| 1 A                              | 5.0 m $\Omega$               | 25.1 $^{\circ}\text{C}$ | 7.1 m $\Omega$               | 85.1 $^{\circ}\text{C}$ |
| 2 A                              | 5.0 m $\Omega$               | 25.1 $^{\circ}\text{C}$ | 7.2 m $\Omega$               | 85.4 $^{\circ}\text{C}$ |
| 3 A                              | 5.0 m $\Omega$               | 25.3 $^{\circ}\text{C}$ | 7.2 m $\Omega$               | 85.7 $^{\circ}\text{C}$ |
| 4 A                              | 5.1 m $\Omega$               | 25.5 $^{\circ}\text{C}$ | 7.2 m $\Omega$               | 86.2 $^{\circ}\text{C}$ |
| 5 A                              | 5.1 m $\Omega$               | 25.8 $^{\circ}\text{C}$ | 7.3 m $\Omega$               | 86.5 $^{\circ}\text{C}$ |
| 6 A                              | 5.1 m $\Omega$               | 26.2 $^{\circ}\text{C}$ | 7.4 m $\Omega$               | 87.1 $^{\circ}\text{C}$ |
| 7 A                              | 5.2 m $\Omega$               | 26.7 $^{\circ}\text{C}$ | 7.5 m $\Omega$               | 87.6 $^{\circ}\text{C}$ |
| 8 A                              | 5.3 m $\Omega$               | 27.4 $^{\circ}\text{C}$ | 7.7 m $\Omega$               | 88.7 $^{\circ}\text{C}$ |
| 9 A                              | 5.4 m $\Omega$               | 28.2 $^{\circ}\text{C}$ | 7.9 m $\Omega$               | 89.8 $^{\circ}\text{C}$ |
| 10 A                             | 5.4 m $\Omega$               | 29.3 $^{\circ}\text{C}$ | 8.3 m $\Omega$               | 91.1 $^{\circ}\text{C}$ |

Figure 7 BDS  $R_{on}$  and case temperature ( $T_c$ ) variation with respect to drain current ( $I_d$ ) at  $V_{D1} = 20$  V

Key insights from the measurements:

- **$R_{on}$  is low and very stable vs. current, especially at 25 $^{\circ}\text{C}$ :**
  - 25 $^{\circ}\text{C}$ : essentially flat at 5.0 m $\Omega$  up to ~3 A, only rising to 5.4 m $\Omega$  at 10 A (~+8% from 1 A)
  - 85 $^{\circ}\text{C}$ : increases gently from 7.0 to 8.3 m $\Omega$  from 0.1 to 10 A (~+19%)
- **Temperature drives  $R_{on}$  more than current does:**
  - At low current (0.1 A): 5.0 to 7.0 m $\Omega$  going 25 to 85 $^{\circ}\text{C}$  (+40%)
  - At 10 A: 5.4 to 8.3 m $\Omega$  (+54%)
  - So, the temperature coefficient is positive, and its apparent impact grows a bit at higher current (because of added self-heating)

## 4 System performance

- **T<sub>CDS</sub> shows modest self-heating with increasing I<sub>drain</sub>:**

- At 25°C ambient: 25.0 to 29.3°C (≈4.3°C) by 10 A
- At 85°C ambient: 85.0 to 91.1°C (≈6.1°C) by 10 A

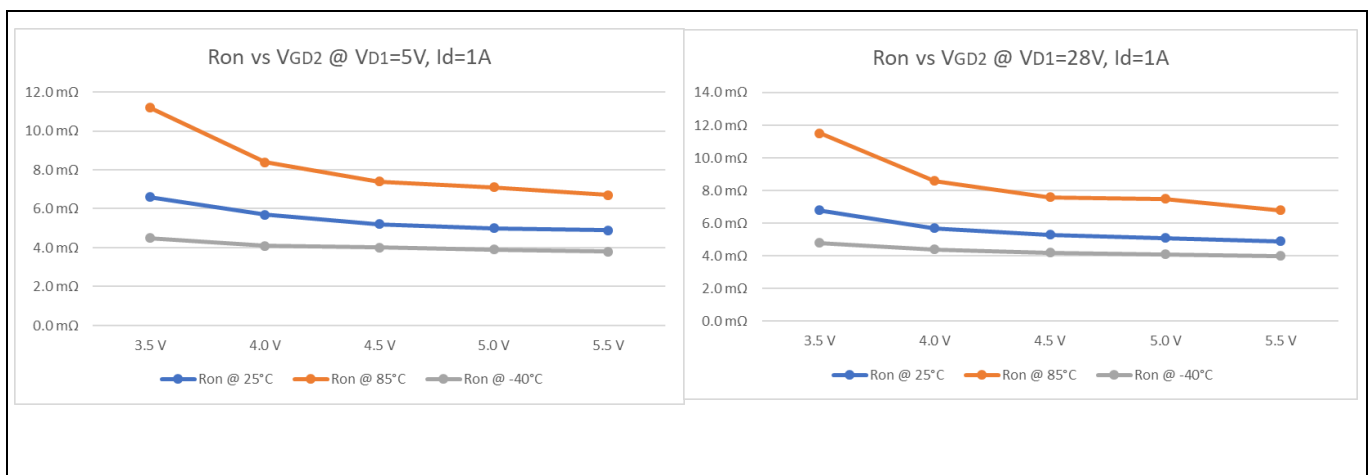
This indicates the setup/device is dissipating more power at higher current, but the thermal rise remains moderate.

- The device behaves like a well-enhanced switch (low, mostly current-independent R<sub>on</sub>), with **ambient temperature being the dominant factor** in conduction loss, and only mild additional heating up to 10 A

### 4.2.3 On-state resistance (R<sub>on</sub>) and gate leakage current (I<sub>gss</sub>) vs. gate-drain voltage (V<sub>GD2</sub>)

**Table 7** Measurement results - R<sub>on</sub> vs. V<sub>GD2</sub> at V<sub>D1</sub> = 5 V and 28 V, I<sub>d</sub> = 1 A

|                  | V <sub>D1</sub> = 5 V, I <sub>Drain</sub> = 1 A |                         |                          | V <sub>D1</sub> = 28 V, I <sub>Drain</sub> = 1 A |                         |                          |
|------------------|-------------------------------------------------|-------------------------|--------------------------|--------------------------------------------------|-------------------------|--------------------------|
| V <sub>GD2</sub> | R <sub>on</sub> at 25°C                         | R <sub>on</sub> at 85°C | R <sub>on</sub> at -40°C | R <sub>on</sub> at 25°C                          | R <sub>on</sub> at 85°C | R <sub>on</sub> at -40°C |
| 3.5 V            | 6.6 mΩ                                          | 11.2 mΩ                 | 4.5 mΩ                   | 6.8 mΩ                                           | 11.5 mΩ                 | 4.8 mΩ                   |
| 4.0 V            | 5.7 mΩ                                          | 8.4 mΩ                  | 4.1 mΩ                   | 5.7 mΩ                                           | 8.6 mΩ                  | 4.4 mΩ                   |
| 4.5 V            | 5.2 mΩ                                          | 7.4 mΩ                  | 4.0 mΩ                   | 5.3 mΩ                                           | 7.6 mΩ                  | 4.2 mΩ                   |
| 5.0 V            | 5.0 mΩ                                          | 7.1 mΩ                  | 3.9 mΩ                   | 5.1 mΩ                                           | 7.5 mΩ                  | 4.1 mΩ                   |
| 5.5 V            | 4.9 mΩ                                          | 6.7 mΩ                  | 3.8 mΩ                   | 4.9 mΩ                                           | 6.8 mΩ                  | 4.0 mΩ                   |



**Figure 8** R<sub>on</sub> variations with respect to gate-drain voltages (V<sub>GD2</sub>) at V<sub>D1</sub> = 5 V and 28 V

Key insights from the measurements are as follows:

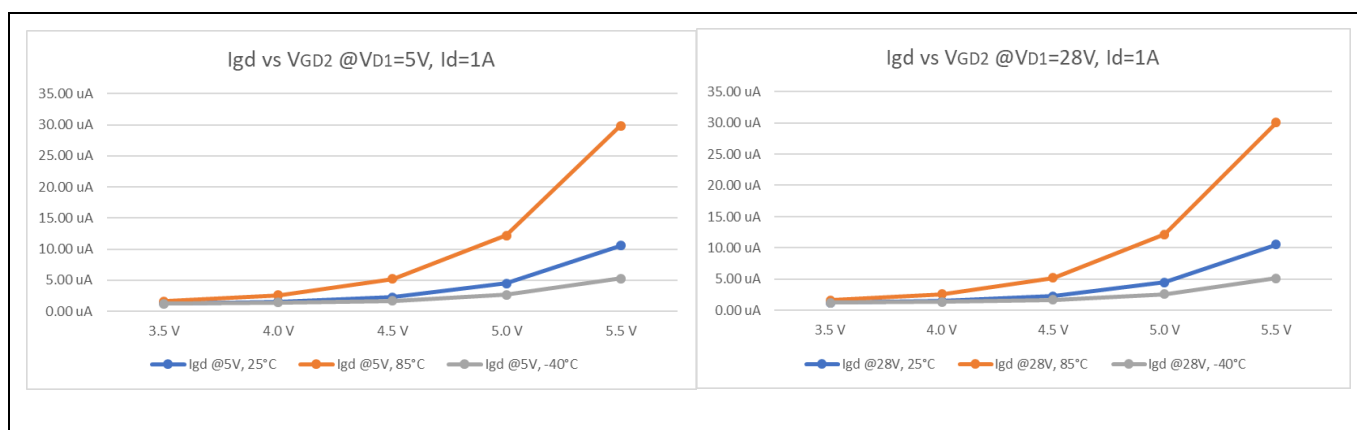
- **R<sub>on</sub> improves with higher V<sub>GD2</sub>, but the benefit tapers off above ~5.0 V**
- **Temperature is the dominant driver of R<sub>on</sub>:**
  - At V<sub>GD2</sub>=5.0 V, V<sub>D1</sub>=5 V: 3.9 mΩ (–40°C) to 5.0 mΩ (25°C) to 7.1 mΩ (85°C) (~+28% from –40 to 25°C, and ~+42% from 25 to 85°C; overall ~1.8× from –40 to 85°C)
  - The temperature penalty is worse at lower V<sub>GD2</sub> (less gate overdrive): at 3.5 V: 4.5 to 6.6 to 11.2 mΩ (~2.5× from –40 to 85°C), versus at 5.5 V: 3.8 to 4.9 to 6.7 mΩ (~1.8×)
- **V<sub>D1</sub> (5 V vs. 28 V) has only a small effect on R<sub>on</sub> at 1 A**, which indicates R<sub>on</sub> is mainly set by V<sub>GD2</sub> and temperature, not V<sub>D1</sub> in this operating range

## 4 System performance

- If you want predictable low  $R_{on}$  across temperature, targeting  $V_{GD2} \approx 5.0$  V captures most of the improvement; dropping to 3.5–4.0 V increases both the absolute  $R_{on}$  and its temperature sensitivity significantly

**Table 8** Measurement results -  $I_{gss}$  vs.  $V_{GD2}$  at  $V_{D1} = 5$  V and 28 V,  $I_d = 1$  A

|           | $V_{D1} = 5$ V, $I_{Drain} = 1$ A |                   |                    | $V_{D1} = 28$ V, $I_{Drain} = 1$ A |                   |                    |
|-----------|-----------------------------------|-------------------|--------------------|------------------------------------|-------------------|--------------------|
| $V_{GD2}$ | $I_{gss}$ at 25°C                 | $I_{gss}$ at 85°C | $I_{gss}$ at -40°C | $I_{gss}$ at 25°C                  | $I_{gss}$ at 85°C | $I_{gss}$ at -40°C |
| 3.5 V     | 1.25 $\mu$ A                      | 1.61 $\mu$ A      | 1.21 $\mu$ A       | 1.22 $\mu$ A                       | 1.62 $\mu$ A      | 1.25 $\mu$ A       |
| 4.0 V     | 1.51 $\mu$ A                      | 2.58 $\mu$ A      | 1.38 $\mu$ A       | 1.52 $\mu$ A                       | 2.61 $\mu$ A      | 1.35 $\mu$ A       |
| 4.5 V     | 2.28 $\mu$ A                      | 5.20 $\mu$ A      | 1.68 $\mu$ A       | 2.28 $\mu$ A                       | 5.18 $\mu$ A      | 1.68 $\mu$ A       |
| 5.0 V     | 4.47 $\mu$ A                      | 12.20 $\mu$ A     | 2.65 $\mu$ A       | 4.52 $\mu$ A                       | 12.15 $\mu$ A     | 2.63 $\mu$ A       |
| 5.5 V     | 10.54 $\mu$ A                     | 29.85 $\mu$ A     | 5.27 $\mu$ A       | 10.56 $\mu$ A                      | 30.06 $\mu$ A     | 5.17 $\mu$ A       |



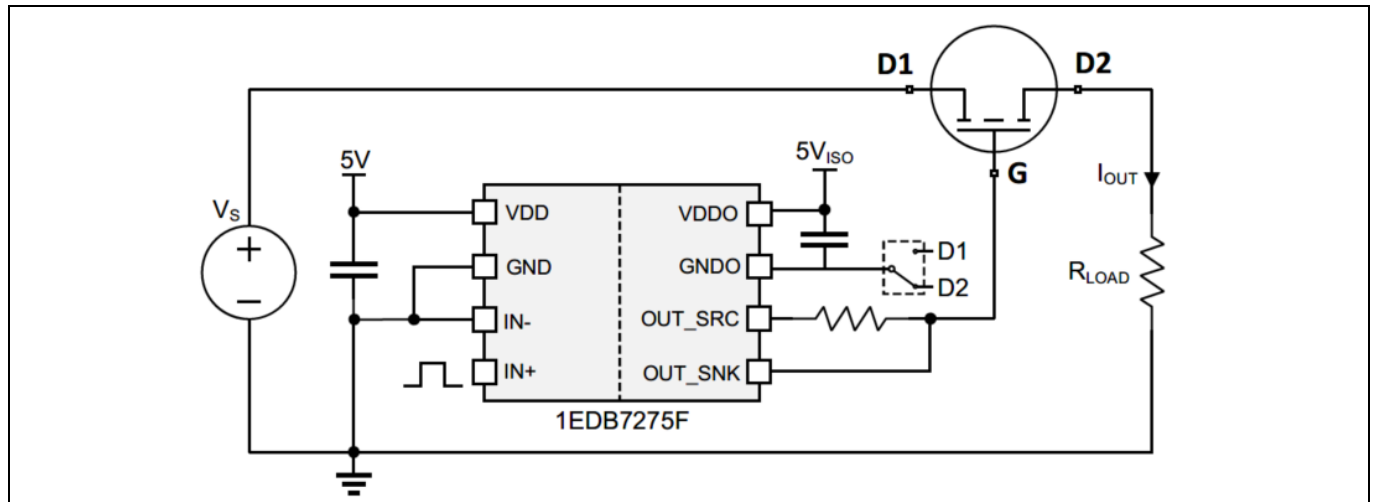
**Figure 9** Gate leakage current ( $I_{gss}$ ) variations with respect to gate-drain voltages ( $V_{GD2}$ ) at  $V_{D1} = 5$  V and 28 V

Key insights from the measurements are as follows:

- $I_{gss}$  increases steeply with  $V_{GD2}$**  (gate-bias dependence) at all temperatures. The higher the gate bias, the more “nonlinear” the leakage growth becomes
- Strong temperature dependence, especially at higher  $V_{GD2}$**
- $V_{D1}$  has negligible influence on  $I_{gss}$ :** results at  $V_{D1}=5$  V and  $V_{D1}=28$  V are essentially the same. This indicates  $I_{gss}$  is dominated by gate-related leakage mechanisms set by  $V_{GD2}$  and temperature, not by drain bias in this range
- Choosing  $V_{GD2} \geq 5.0$  V will materially increase gate leakage—particularly at 85°C—so if standby current or gate-drive source impedance matters, 5.0 to 5.5 V should be selected with that leakage budget in mind

#### 4.3 Evaluation with EVAL\_GD\_BDS\_GaN gate driver board

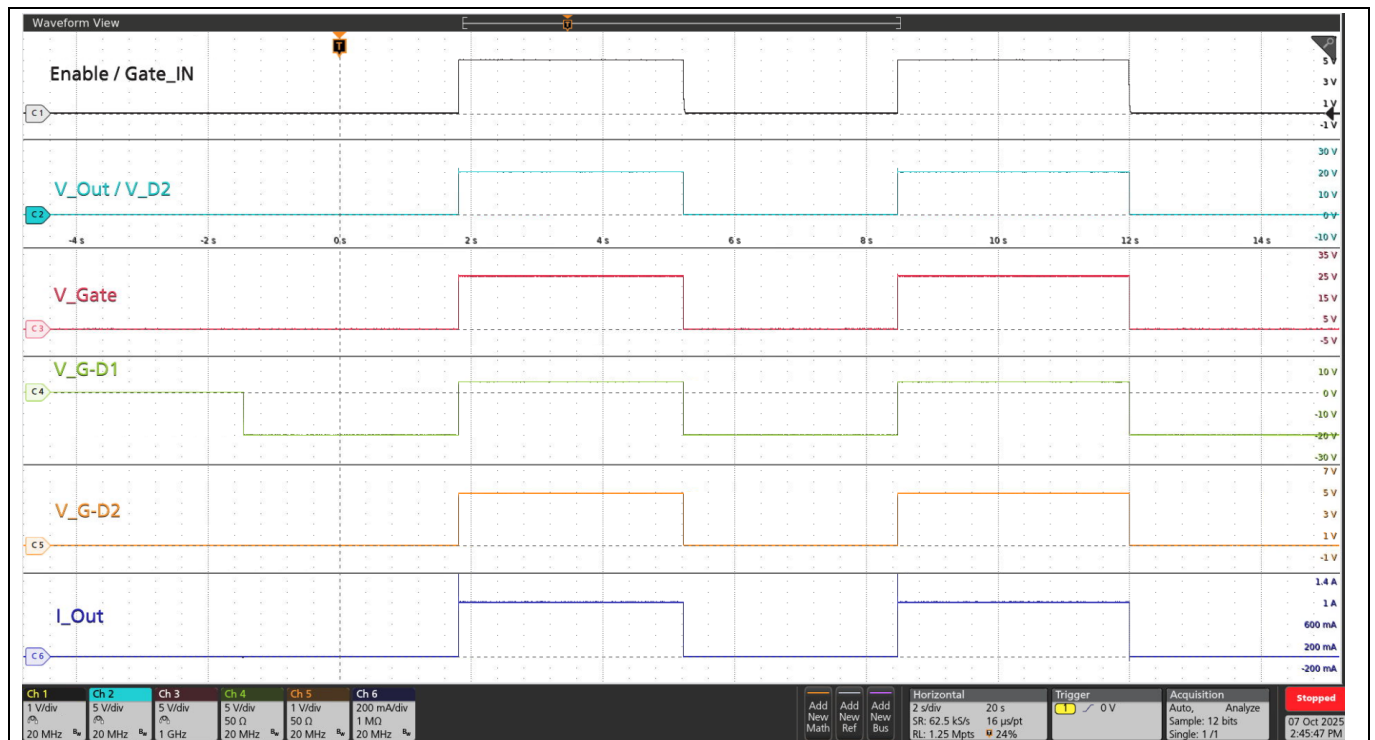
##### 4.3.1 Test setup



**Figure 10** GaN BDS as a high-side switch using 1EDB7275F isolated gate driver

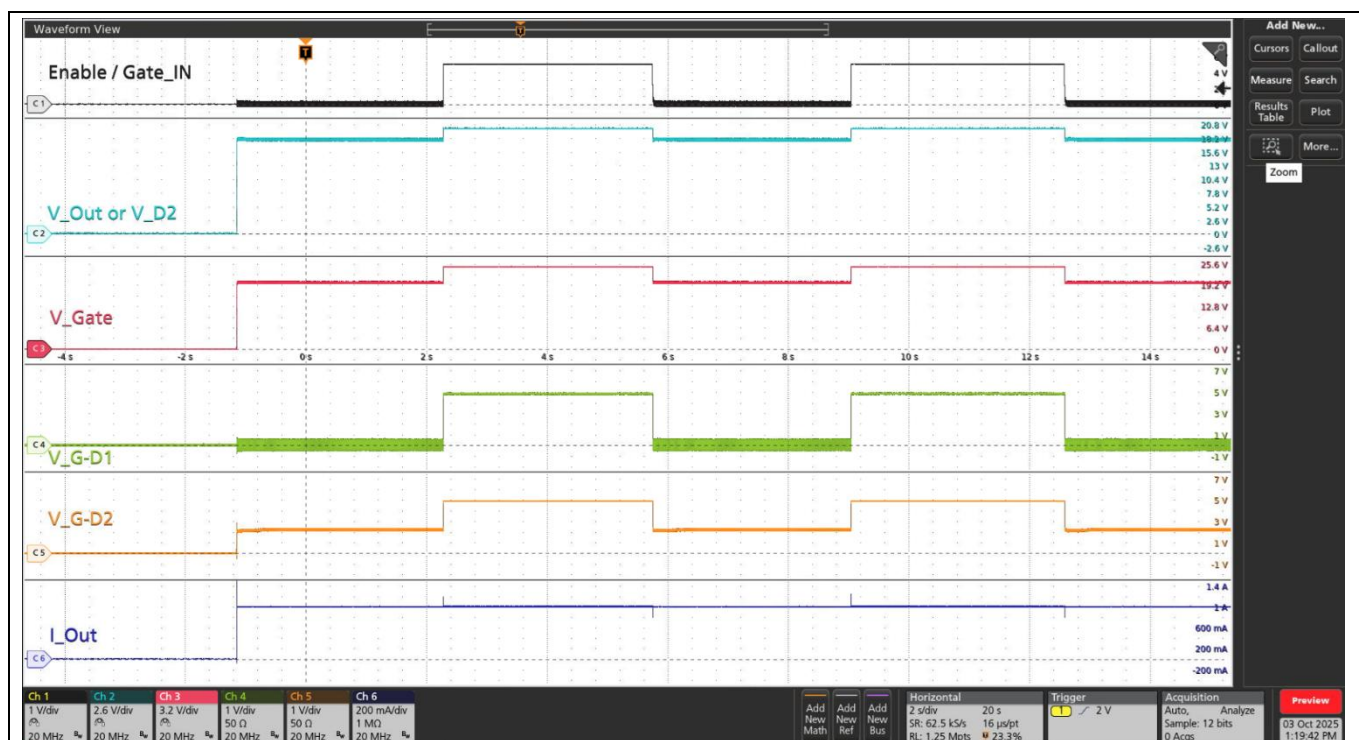
Figure 10 shows high-side operation of the GaN BDS using the isolated gate driver 1EDB7275F from Infineon, for unidirectional current flow. The gate reference selector switch allows the gate return path to be connected to either D1 or D2, depending on the intended direction of current flow. The 1EDB7275F has a UVLO threshold of 4.2 V. Therefore, it can be powered directly from a 5 V supply.

##### 4.3.2 Cyclic turn on/off waveform



**Figure 11** Unidirectional current flow and gate reference to D2

## 4 System performance



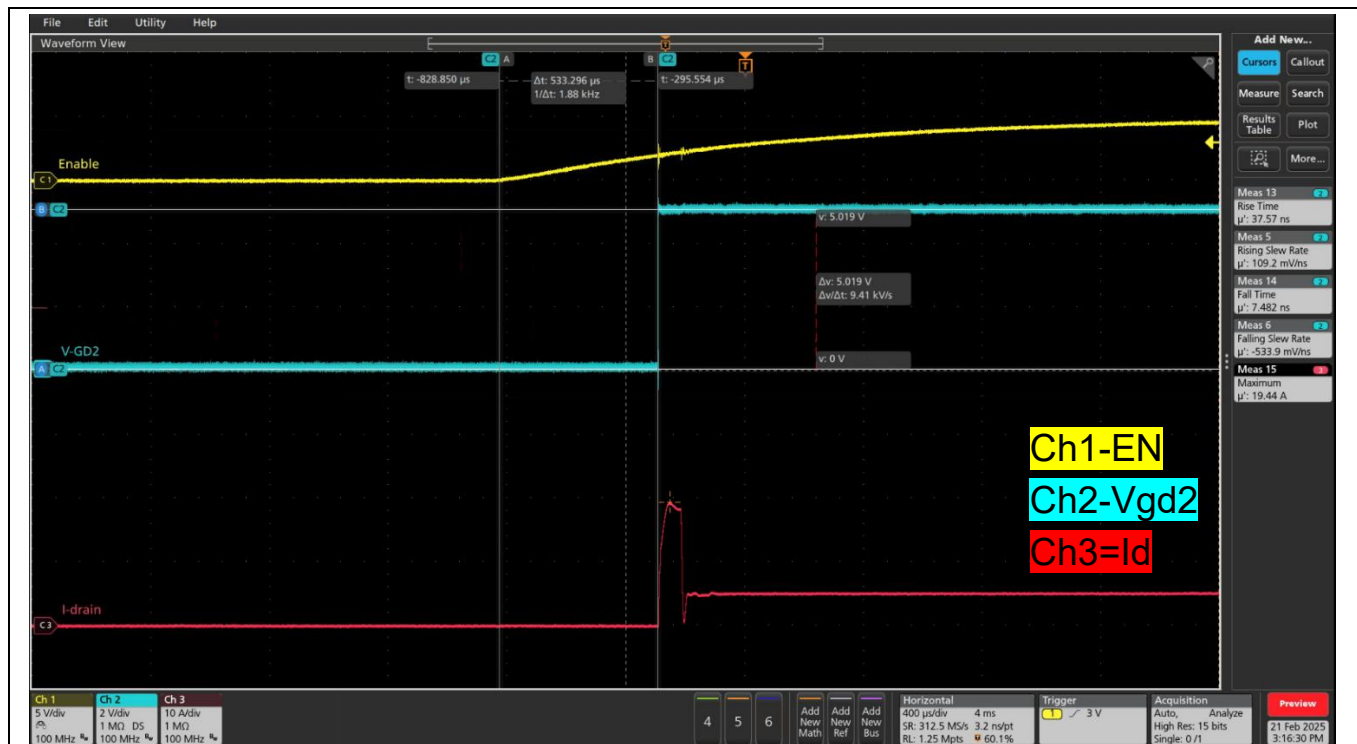
**Figure 12 Unidirectional current flow and gate reference to D1**

For the circuit in [Figure 10](#) (with  $V_S = 20\text{ V}$  and  $R_{Load} = 20\ \Omega$ ), [Figure 11](#) shows the corresponding waveforms when the gate voltage is referenced to D2. When the power supplies ( $V_S$  and  $V_{DD}$ ) are on and Enable/IN is inactive, gate voltage  $V_G = V_{GD2} = 0\text{ V}$ , and thus  $V_{GD1} = -20\text{ V}$ . Asserting Enable/IN causes  $V_{GD2}$  to increase to  $5\text{ V}$  ( $V_G = 25\text{ V}$ ), thereby turning on the GaN BDS.

For the same circuit, when the gate is referenced to D1, [Figure 12](#) shows the corresponding waveforms. When the power supplies ( $V_S$ ,  $V_{DD}$ , and  $V_{DDO}$ ) are on and Enable/IN is inactive, gate voltage  $V_G = V_{GD1} = 20\text{ V}$ , which turns on the GaN BDS and allows current flow from D1 to D2, with a significant voltage drop ( $V_{D1D2} \approx 2\text{ V}$ ), similar to diode mode. Asserting Enable/IN increases  $V_{GD1}$  to  $5\text{ V}$  ( $V_G = 25\text{ V}$ ), fully turning on the GaN BDS and decreasing the voltage drop to  $R_{ON} \times I_{OUT}$ .

## 4 System performance

## 4.3.3 Startup behavior

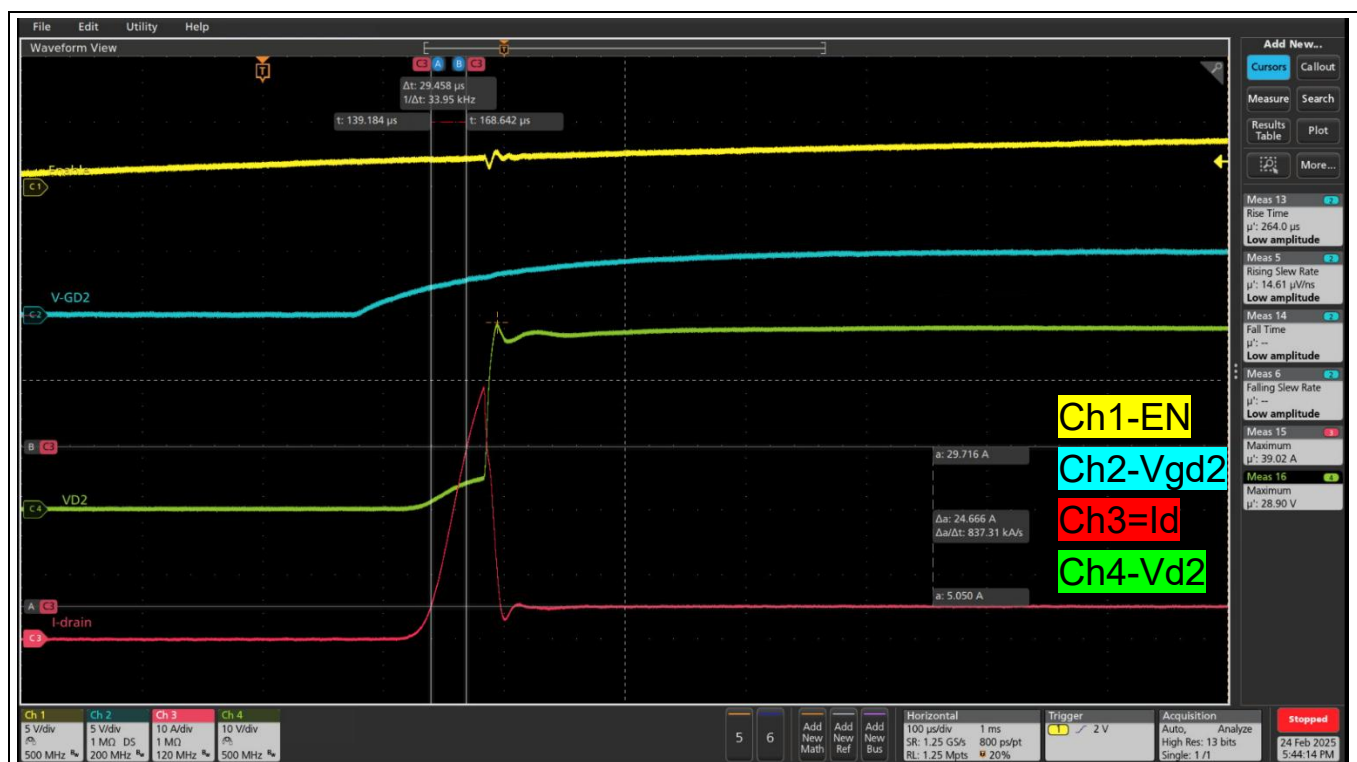


**Figure 13** Turn on without RC delay on gate drive path-  $V_{D1}=5\text{ V}$ ,  $I_d=10\text{ A}$  (load),  $V_{GD2} = 0\text{ V}$  to  $5\text{ V}$ ,  $I_{d\_max} = 19.44\text{ A}$ ,  $t_{I\_max} = 120\text{ }\mu\text{s}$



**Figure 14** Turn on without RC delay on gate drive path-  $V_{D1}=20\text{ V}$ ,  $I_d=5\text{ A}$  (load),  $V_{GD2} = 0\text{ V}$  to  $5\text{ V}$ ,  $I_{d\_max} = 62.47\text{ A}$ ,  $t_{I\_max} = 32.6\text{ }\mu\text{s}$

## 4 System performance



**Figure 15** Turn on with RC (1 kΩ, 100 nF) delay on gate drive path-  $V_{D1}=28\text{ V}$ ,  $I_d=5\text{ A}$  (load),  $V_{GD2} = 0\text{ V}$  to  $5\text{ V}$ ,  $I_{d\_max} = 39.02\text{ A}$ ,  $dI/dt = 0.837\text{ A/us}$

Since the isolated gate driver voltage is supplied externally, turn-on is fast with negligible delay. However, rapid turn-on can cause large inrush currents, which can damage the BDS if not controlled. Additionally, the inrush current increases with the increase in input voltage applied to the drain terminal.

By using an RC delay circuit on the gate terminal, the turn on can be slowed and inrush current can be limited.

## **5 Conclusion**

This user guide provides a comprehensive overview of the working and results for the 40 V, 4.2 mΩ, GaN BDS evaluation board, enabling the user to start experimenting and working with the 2.1 x 2.1 mm WLCSP package BDS.

The board demonstrates the on-state resistance and device temperature variations with respect to the increasing drain current, as well as the variations in the on-state resistance with the changes in the gate-drain voltage.

Note that these device parameter values measured are strictly for the particular device tested and may vary. However, these values will always be within the limits specified in BDS datasheet.

## 6 Related resources

- [Gallium nitride \(GaN\)](#) webpage
- EVAL\_GD\_BDS\_GaN Evaluation Board
- Infineon Developer Community: [GaN](#) forum

## References

- [1] Infineon Technologies AG. Datasheet (2026): IGK048B041S V 1.1; [Available online](#)
- [2] Infineon Technologies AG. Whitepaper (2026): *Gate driving techniques for medium voltage GaN bidirectional switches*; [Available online](#)

## Glossary

**Table 9      Abbreviations**

| Abbreviation | Expansion             |
|--------------|-----------------------|
| BDS          | Bidirectional switch  |
| EN           | Enable                |
| EVAL         | Evaluation            |
| GaN          | Gallium Nitride       |
| GD           | Gate driver           |
| PCB          | Printed circuit board |

### Revision history

| Document revision | Date       | Description of changes |
|-------------------|------------|------------------------|
| V 1.0             | 2026-06-15 | Initial release        |

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Customer shall not touch the Evaluation Board during operation and keep a safe distance.

Customer shall not touch the Evaluation Board after disconnecting the power supply, several components may still store electrical voltage and can discharge through physical contact. Several parts, like heat sinks and transformers, may still be very hot. Allow the components to cool before touching or servicing.

The electrical installation must be completed in accordance with the appropriate safety requirements.